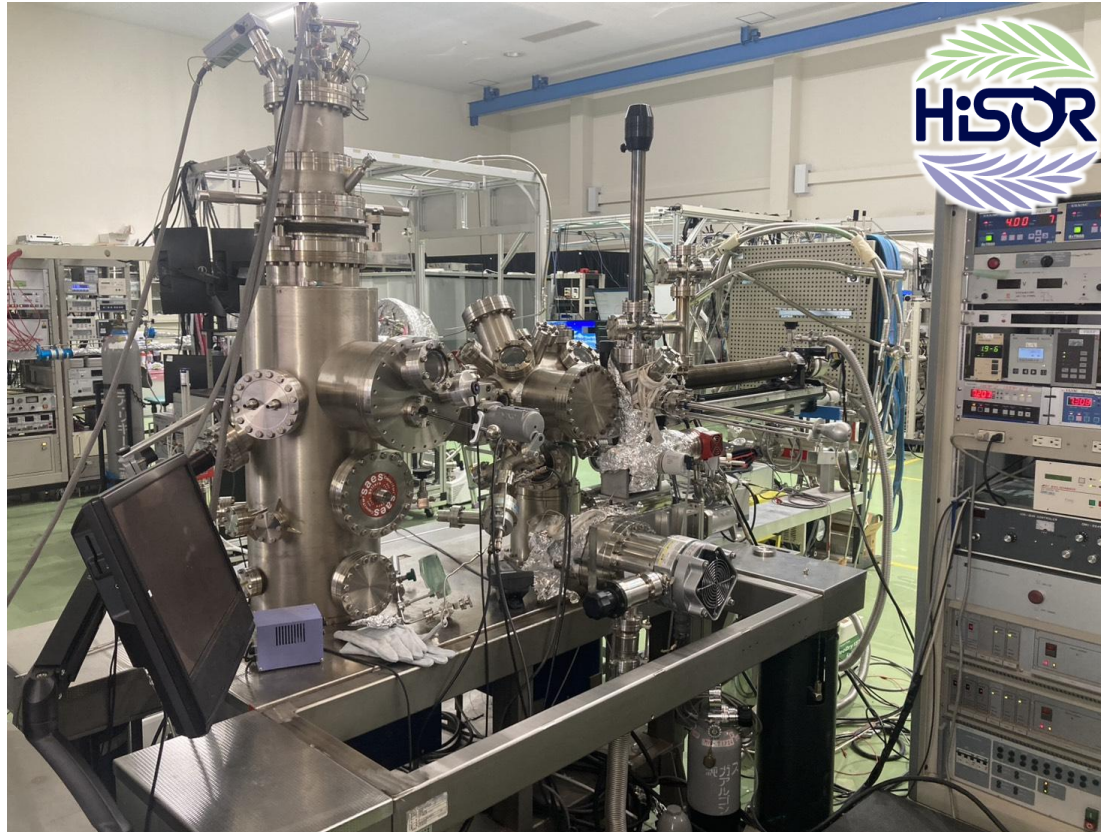
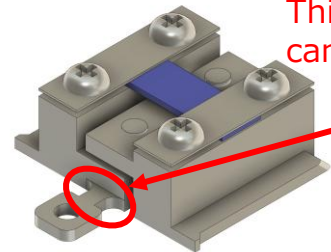


Low-temperature scanning tunneling microscope for microscopic structural characterization of solids



This part should be necked, otherwise you cannot transfer the sample to STM head.



- ❑ UHV condition ($\sim 2e-10$ Pa)
- ❑ Temperature: 4 K, 77 K, 300 K
- ❑ Sample holder: Omicron type
- ❑ Surface treatment: Ar-sputtering, annealing (DC heating only)
- ❑ LEED is available for the structural characterization